## Supplementary information for Three-dimensional deconvolution for large-angle illumination annular dark-field scanning transmission electron microscopy depth sectioning

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## Supplementary Note 1: Formalizing 3D deconvolution as linear regression

In this section, we formalize 3D deconvolution as linear regression. Here, we denote by  $\otimes_i$  (i=1,2,3) the 1D, 2D, and 3D convolution operators, respectively. First, we consider the 1D convolution. Since the n-th entry of the convolution of  $\boldsymbol{a} = [a_0,a_1,\cdots,a_{M-1}]^{\top} \in \mathbb{R}^M$  and  $\boldsymbol{b} = [b_0,b_1,\cdots,b_{M-1}]^{\top} \in \mathbb{R}^N$  is given by

$$[\boldsymbol{a} \otimes_1 \boldsymbol{b}]_n = \sum_i a_{n-i} b_i, \tag{S1}$$

the convolution can be expressed as

$$\mathbf{a} \otimes_{1} \mathbf{b} = \begin{bmatrix} a_{0} & 0 & 0 & \cdots & 0 \\ a_{1} & a_{0} & 0 & \cdots & 0 \\ a_{2} & a_{1} & a_{0} & \ddots & \vdots \\ \vdots & \vdots & \vdots & \ddots & 0 \\ a_{M-1} & a_{M-2} & a_{M-3} & a_{0} \\ 0 & a_{M-1} & a_{M-2} & \ddots & \vdots \\ \vdots & \ddots & \ddots & \ddots & a_{M-3} \\ 0 & \cdots & 0 & a_{M-1} & a_{M-2} \\ 0 & \cdots & 0 & 0 & a_{M-1} \end{bmatrix} \begin{bmatrix} b_{0} \\ b_{1} \\ b_{2} \\ \vdots \\ b_{N-1} \end{bmatrix}$$

$$(S2)$$

$$Toeplitz matrix$$

$$=: T(\mathbf{a})\mathbf{b}.$$

Here,  $T(a) \in \mathbb{R}^{(M+N-1)\times N}$  denotes the Toeplitz matrix.

Next, we consider the 2D convolution. The (m, n)-th entry of the convolution of  $\mathbf{A} \in \mathbb{R}^{M_1 \times M_2}$  and  $\mathbf{B} \in \mathbb{R}^{N_1 \times N_2}$  is given by

$$[\boldsymbol{A} \otimes_{2} \boldsymbol{B}]_{m,n} = \sum_{j} \underbrace{\sum_{i} A_{m-i,n-j} B_{i,j}}_{\text{m-th entry of 1D convolution}}$$

$$= \sum_{j} [\boldsymbol{a}_{n-j} \otimes_{1} \boldsymbol{b}_{j}]_{m} \ (\because \text{Eq. (S1)})$$

$$= \sum_{j} [\boldsymbol{T}(\boldsymbol{a}_{n-j}) \boldsymbol{b}_{j}]_{m} \ (\because \text{Eq. (S2)})$$

$$= \left[\sum_{j} \boldsymbol{T}(\boldsymbol{a}_{n-j}) \boldsymbol{b}_{j}\right]_{m} \ ,$$
(S3)

where  $\boldsymbol{a}_{n-j} = [A_{0,n-j}, A_{1,n-j}, \cdots, A_{M_1-1,n-j}]^{\top}$  and  $\boldsymbol{b}_i = [B_{0,j}, B_{1,j}, \cdots, B_{N_1-1,j}]^{\top}$  are the (n-j)- and j-th column of  $\boldsymbol{A}$  and  $\boldsymbol{B}$ , respectively. Thus, the 2D convolution can be expressed as

can be expressed as 
$$\operatorname{vec}(A \otimes_2 B) = \begin{bmatrix} \sum_j T(a_{0-j})b_j \\ \sum_j T(a_{M_2-j})b_j \\ \vdots \\ \sum_j T(a_{M_2-j})b_j \end{bmatrix}$$

$$= \begin{bmatrix} T(a_0) & 0 & 0 & \cdots & 0 \\ T(a_1) & T(a_0) & 0 & \cdots & 0 \\ T(a_2) & T(a_1) & T(a_0) & \ddots & \vdots \\ \vdots & \vdots & \vdots & \ddots & 0 \\ T(a_{M_2-1}) & T(a_{M_2-2}) & T(a_{M_2-3}) & T(a_0) \\ 0 & T(a_{M_2-1}) & T(a_{M_2-2}) & \ddots & \vdots \\ \vdots & \ddots & \ddots & \ddots & T(a_{M_2-3}) \\ 0 & \cdots & 0 & T(a_{M_2-1}) & T(a_{M_2-2}) \\ 0 & \cdots & 0 & 0 & T(a_{M_2-1}) \end{bmatrix} \begin{bmatrix} b_0 \\ b_1 \\ b_2 \\ \vdots \\ b_{N_2-1} \end{bmatrix}$$

$$=: T_2(A) \operatorname{vec}(B),$$
 (S4)

where  $T_2(A) \in \mathbb{R}^{(M_1+N_1-1)(M_2+N_2-1)\times N_1N_2}$  denotes the doubly block Toeplitz matrix and  $\text{vec}(\cdot)$  represents the vectorization. Hence, the 2D convolution can be expressed as the matrix multiplication.

Similarly, the vectorization of 3D convolution between  $\mathcal{A} \in \mathbb{R}^{M_1 \times M_2 \times M_3}$  and  $\mathcal{B} \in \mathbb{R}^{N_1 \times N_2 \times N_3}$  is expressed as

$$\operatorname{vec}(\mathcal{A} \otimes_{3} \mathcal{B}) = \begin{bmatrix} T_{2}(A_{0}) & 0 & 0 & \cdots & 0 \\ T_{2}(A_{1}) & T_{2}(A_{0}) & 0 & \cdots & 0 \\ T_{2}(A_{2}) & T_{2}(A_{1}) & T_{2}(A_{0}) & \ddots & \vdots \\ \vdots & \vdots & \vdots & \ddots & 0 \\ T_{2}(A_{M_{3}-1}) & T_{2}(A_{M_{3}-2}) & T_{2}(A_{M_{3}-3}) & T_{2}(A_{0}) \\ 0 & T_{2}(A_{M_{3}-1}) & T_{2}(A_{M_{3}-2}) & \ddots & \vdots \\ \vdots & \ddots & \ddots & \ddots & T_{2}(A_{M_{3}-3}) \\ 0 & \cdots & 0 & T_{2}(A_{M_{3}-1}) & T_{2}(A_{M_{3}-2}) \\ 0 & \cdots & 0 & 0 & T_{2}(A_{M_{3}-1}) \end{bmatrix} = : T_{3}(\mathcal{A}) \operatorname{vec}(\mathcal{B}),$$

$$(S5)$$

where

$$\mathbf{A}_{i} = \begin{bmatrix}
A_{0,0,i} & A_{0,1,i} & \cdots & A_{0,M_{2}-1,i} \\
A_{1,0,i} & A_{1,1,i} & \cdots & A_{1,M_{2}-1,i} \\
\vdots & \vdots & \ddots & \vdots \\
A_{M_{1}-1,0,i} & A_{M_{1}-1,1,i} & \cdots & A_{M_{1}-1,M_{2}-1,i}
\end{bmatrix} \in \mathbb{R}^{M_{1} \times M_{2}},$$

$$\mathbf{B}_{i} = \begin{bmatrix}
B_{0,0,i} & B_{0,1,i} & \cdots & B_{0,N_{2}-1,i} \\
B_{1,0,i} & B_{1,1,i} & \cdots & B_{1,N_{2}-1,i} \\
\vdots & \vdots & \ddots & \vdots \\
B_{N_{1}-1,0,i} & B_{N_{1}-1,1,i} & \cdots & B_{N_{1}-1,N_{2}-1,i}
\end{bmatrix} \in \mathbb{R}^{N_{1} \times N_{2}}.$$
(S6)

Here, we model ADF-STEM depth sectioning as

$$I = P \otimes_3 O + n', \tag{S7}$$

where I, O, P represent the intensity of an ADF-STEM depth sectioning image, an 3D object function, and a 3D probe function, respectively, and  $n \sim \mathcal{N}(\mathbf{0}, \gamma^{-1}\mathbf{E})$  denotes the additive white Gaussian noise (AWGN). Using Eq. (S5), we obtain

$$y = Ax + n, (S8)$$

where  $\mathbf{y} = \text{vec}(\mathbf{I}), \mathbf{A} = \mathbf{T}_3(\mathbf{P}), \mathbf{x} = \text{vec}(\mathbf{O}), \mathbf{n} = \text{vec}(\mathbf{n}')$ , respectively. This is equaivalent to Eq. (2) in the main text. Therefore, 3D deconvolution, which recovers the 3D object function  $\mathbf{O}$  from the intensity of an ADF-STEM depth sectioning image  $\mathbf{I}$ , can be formalized as linear regression.

 ${\bf Table~S1}~{\rm Estimated~effective~source~size~of~ADF-STEM~depth~sectioning~image~of~Si~at~various~eletron~dose.}$ 

Electron dose (e <sup>-</sup> /Å <sup>2</sup> )	$10^{5}$	$2 \times 10^5$	$5 \times 10^5$	$10^{6}$	$2 \times 10^6$	$5 \times 10^6$	$10^{7}$	Infinite
Estimated effective	59.0	54.5	52.7	50.0	42.5	48.6	48.1	47.3
source size (pm)								